



S/N 09/725,646

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: HUANG ET AL. Examiner: T.R. SUNDARAM  
Serial No.: 09/725,646 Group Art Unit: 2858  
Filed: NOVEMBER 29, 2000 Docket No.: 10139.27USC1  
Title: TEST METHODS, SYSTEMS, AND PROBES FOR HIGH-FREQUENCY  
WIRELESS-COMMUNICATIONS DEVICES

CERTIFICATE UNDER 37 CFR 1.8:

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail, with sufficient postage, in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231 on October 9, 2002.

By: 

Name: Dana C. Reichen

#6/Abdt  
R. W. A  
10/17/02

AMENDMENT AND RESPONSE

Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

The applicants provide the following amendments and remarks in response to the office action mailed on April 9, 2002. A petition for a three-month extension of time and related fee are being filed concurrently herewith.

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AmendmentsA. In the SpecificationIn the Abstract

Please delete the Abstract on page 19, lines 3-21 and replace it with the following new Abstract:

A<sup>1</sup> -- A test probe for a high-frequency device having an electronic circuit with two or more contact regions. The test probe comprises two or more signal probe tips. Each signal probe tip has a contact surface area for contacting one of the contact regions of the device. A ground probe has a ground contact surface with a surface area substantially greater than the contact surface area of the one signal probe tip for contacting another one of the contact regions of the electronic circuit. The ground probe is positioned between at least two of the signal probes.--